Problem 1. [Sequential testing in Gaussian case] Let X, X_1, X_2, \ldots be an i.i.d. sequence of normal variables $N(\mu, 1)$. Consider the simple binary testing problem: $H_0: \mu = 0, H_1: \mu = \mu_0 > 0$. For simplicity, let us specify equal probabilities of error, that is, $\alpha = 1 - \beta \ll \frac{1}{2}$.

(i) Show that the optimal cut-off for the (non-sequential) likelihood ratio test is to reject the null if $\log LR_n \ge 0$. Conclude that the number of samples required for a specified size α is

$$\mathfrak{n} = \left\lceil \frac{2(\Phi^{-1}(1-\alpha))^2}{\mu_0} \right\rceil$$

- (ii) Develop the corresponding SPRT and approximate its expected stopping time using the formulas developed in the lecture. Use both μ_0 and α as parameters that can take some fixed values. What do you observe?
- (iii) Propose simulations that allow you to estimate the expected stopping time. What is the estimated variance?
- (iv) Suppose that each additional sample incurs a cost c > 0. Consider the objective of minimizing the expected total cost, defined as:

$$\mathbb{E}[N] \cdot \mathbf{c} + \mathbb{P}_{0}(\text{reject } H_{0}) + \mathbb{P}_{1}(\text{accept } H_{0}).$$

It is intuitively clear that a modified Wald test should aim to terminate earlier. We now modify the SPRT so that the stopping boundaries are of the form:

$$\gamma_0' = rac{1-eta}{1-lpha} e^{-\lambda c}, \quad \gamma_1' = rac{eta}{lpha} e^{\lambda c},$$

where $\lambda > 0$ is a parameter that accounts for the sampling cost. In simulations analyse the expected total cost for different **c** and different values of $\lambda \in (0, \frac{1}{2}\mu_0^2)$.

Problem 2. (Requires material from later lectures) Let $X \in \mathbb{R}^{n \times d}$ be a random matrix with i.i.d. zero mean entries that are σ -sub-Gaussian. Denote by S^{n-1} the unit sphere in \mathbb{R}^n and by \mathbb{B}_2^n the corresponding unit ball.

- (i) Show that $u^T X v$ is a σ -sub-Gaussian random variable for any $u \in \mathbb{B}_2^n$, $v \in \mathbb{B}_2^d$.
- (ii) The operator norm ||X|| is defined as $||X|| := \sup_{\nu \neq 0} \frac{||X\nu||}{||\nu||}$. Show that

$$\|X\| = \max_{u \in S^{n-1}} \max_{\nu \in S^{d-1}} u^{\mathsf{T}} X \nu = \max_{u \in \mathbb{B}_2^n} \max_{\nu \in \mathbb{B}_2^d} u^{\mathsf{T}} X \nu.$$

(iii) Using (i) and (ii), show that there exists a constant C > 0 such that $\mathbb{E}||X|| \le C(\sqrt{n} + \sqrt{d})$.